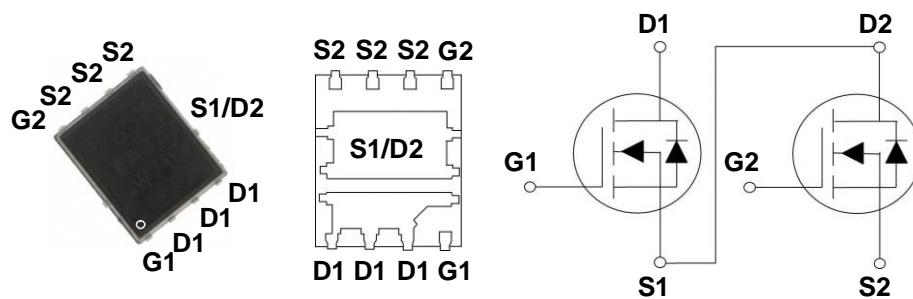


General Description

These N-Channel enhancement mode power field effect transistors are using trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency fast switching applications.

PPAK5x6 Asymmetric Dual Pin Configuration



Features

- Improved dv/dt capability
- Fast switching
- 100% EAS Guaranteed
- Green Device Available

Applications

- MB / VGA / Vcore
- POL Buck Applications
- SMPS 2nd SR



Absolute Maximum Ratings $T_c=25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Q1	Q2	Units
V_{DS}	Drain-Source Voltage	40	40	V
V_{GS}	Gate-Source Voltage	± 20	± 20	V
I_D	Drain Current – Continuous ($T_c=25^\circ\text{C}$)	39	60	A
	Drain Current – Continuous ($T_c=100^\circ\text{C}$)	24.6	37.9	A
I_{DM}	Drain Current – Pulsed ¹ , Chip/Package Limit	156	240	A
EAS	Single Pulse Avalanche Energy ²	58	88	mJ
IAS	Single Pulse Avalanche Current ²	34	42	A
P_D	Power Dissipation ($T_c=25^\circ\text{C}$)	34.7	41.7	W
	Power Dissipation – Derate above 25°C	0.28	0.33	W/°C
T_{STG}	Storage Temperature Range	-55 to 150		°C
T_J	Operating Junction Temperature Range	-55 to 150		°C

Thermal Characteristics

Symbol	Parameter	Typ.	Max.	Unit
$R_{\theta JA}$	Q1	---	62	°C/W
		---	62	°C/W
$R_{\theta JC}$	Q1	'---	3.6	°C/W
		'---	3	°C/W



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Electrical Characteristics ($T_J=25\text{ }^\circ\text{C}$, unless otherwise noted)

Static State Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit	
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =250uA	Q1	40	---	V	
			Q2	40	---	V	
$\Delta BV_{DSS}/\Delta T_J$	BV _{DSS} Temperature Coefficient	Reference to 25°C , I _D =1mA	Q1	---	---	V/°C	
			Q2	---	0.03	V/°C	
I _{DSS}	Drain-Source Leakage Current	V _{DS} =40V , V _{GS} =0V , T _J =25°C	Q1	---	1	uA	
			Q2	---	1	uA	
		V _{DS} =32V , V _{GS} =0V , T _J =125°C	Q1	---	10	uA	
			Q2	---	10	uA	
I _{GSS}	Gate-Source Leakage Current	V _{GS} =±20V , V _{DS} =0V	Q1	---	±100	nA	
			Q2	---	±100	nA	
R _{DSON}	Static Drain-Source On-Resistance ³	V _{GS} =10V , I _D =8A	Q1	9	13	mΩ	
		V _{GS} =10V , I _D =10A	Q2	5.5	6.8	mΩ	
		V _{GS} =4.5V , I _D =6A	Q1	11.5	17	mΩ	
		V _{GS} =4.5V , I _D =5A	Q2	7.2	9.5	mΩ	
V _{GS(th)}	Gate Threshold Voltage	V _{GS} =V _{DS} , I _D =250uA	Q1	1	1.6	V	
			Q2	1	1.6	V	
$\Delta V_{GS(th)}$	V _{GS(th)} Temperature Coefficient		Q1	---	---	mV/°C	
			Q2	---	-5	mV/°C	
g _f	Forward Transconductance	V _{DS} =10V , I _D =1A	Q1	5	---	S	
		V _{DS} =10V , I _D =3A	Q2	10	---	S	

Dynamic Characteristics

Q _g	Total Gate Charge ^{3, 4}	V _{DS} =20V , V _{GS} =4.5V , I _D =10A	Q1	---	13	26	nC
Q _{gs}	Gate-Source Charge ^{3, 4}		Q2	---	16.2	32	
Q _{gd}	Gate-Drain Charge ^{3, 4}		Q1	---	4	8	
T _{d(on)}	Turn-On Delay Time ^{3, 4}		Q2	---	3.85	7	
T _r	Rise Time ^{3, 4}		Q1	---	5.3	10	
T _{d(off)}	Turn-Off Delay Time ^{3, 4}		Q2	---	6.05	12	
T _f	Fall Time ^{3, 4}	V _{DD} =20V , V _{GS} =10V , R _G =6Ω	Q1	---	8	16	ns
			Q2	---	13.6	25	
			Q1	---	3.2	8	
			Q2	---	2.5	5	
		I _D =1A	Q1	---	26.4	52	
			Q2	---	68	120	
			Q1	---	3.8	8	
			Q2	---	5	10	



C_{iss}	Input Capacitance	$V_{DS}=25V$, $V_{GS}=0V$, $F=1MHz$	Q1	---	1088	2000	pF
C_{oss}	Output Capacitance		Q2	---	1540	2500	
C_{rss}	Reverse Transfer Capacitance		Q1	---	110	200	
R_g	Gate resistance		Q2	---	171	330	
			Q1	---	80	160	
			Q2	---	115	220	
		$V_{GS}=0V$, $V_{DS}=0V$, $F=1MHz$	Q1	---	3	---	Ω
			Q2	---	1.2	---	Ω

Drain-Source Diode Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
I_s	Continuous Source Current	$V_G=V_D=0V$, Force Current	Q1	---	---	39 A
I_{SM}	Pulsed Source Current ³		Q2	---	---	60 A
V_{SD}	Diode Forward Voltage ³		Q1	---	---	78 A
			Q2	---	---	120 A
		$V_{GS}=0V$, $I_s=1A$, $T_J=25^\circ C$	Q1	---	---	1 V
			Q2	---	---	1 V

Note :

1. Repetitive Rating : Pulsed width limited by maximum junction temperature.
2. $V_{DD}=25V$, $V_{GS}=10V$, $L=0.1mH$, Q1: $I_{AS}=34A$, Q2: $I_{AS}=42A$, $R_G=25\Omega$, Starting $T_J=25^\circ C$.
3. The data tested by pulsed , pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$.
4. Essentially independent of operating temperature.



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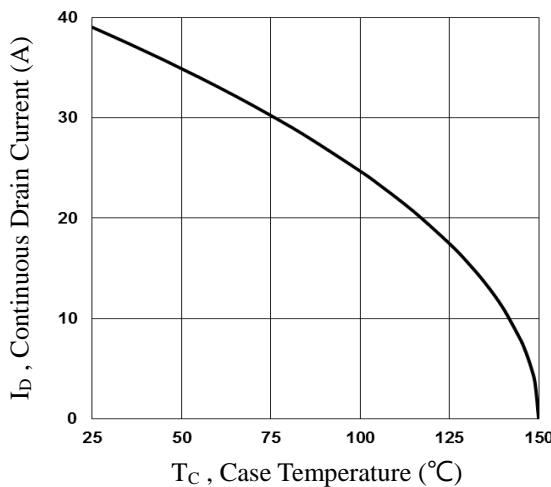


Fig.1 Q1 Continuous Drain Current vs. T_C

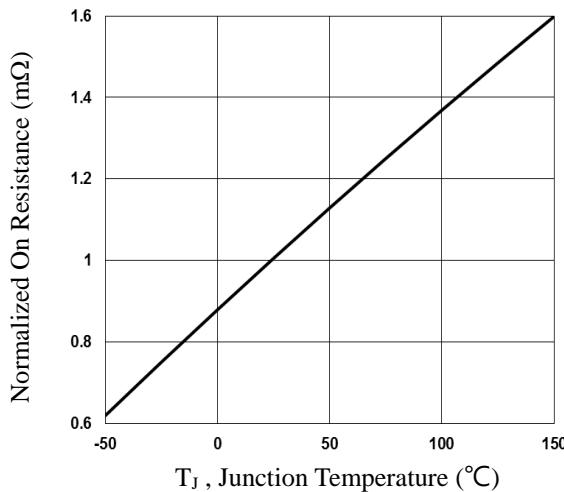


Fig.2 Q1 Normalized R_{DSON} vs. T_J

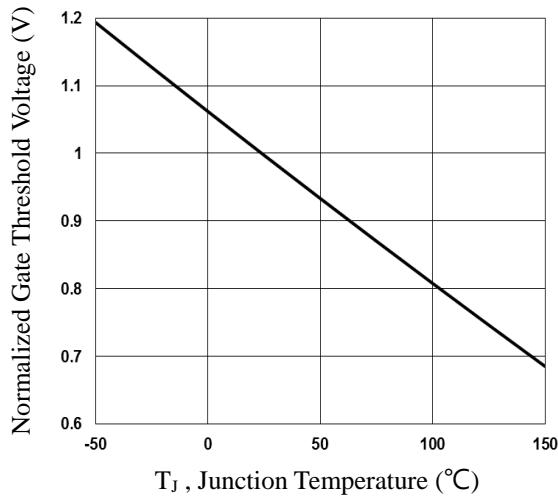


Fig.3 Q1 Normalized V_{th} vs. T_J

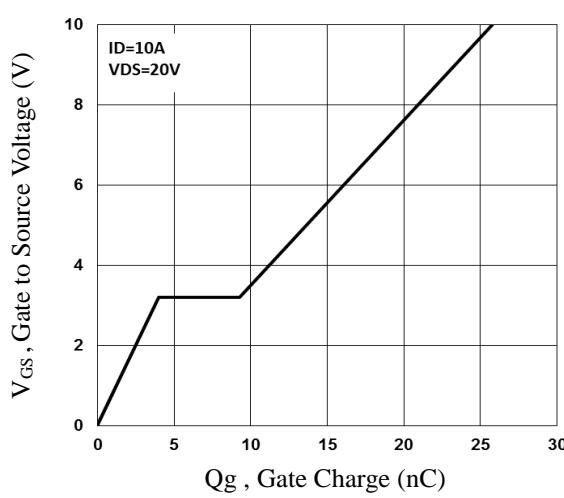


Fig.4 Q1 Gate Charge Waveform

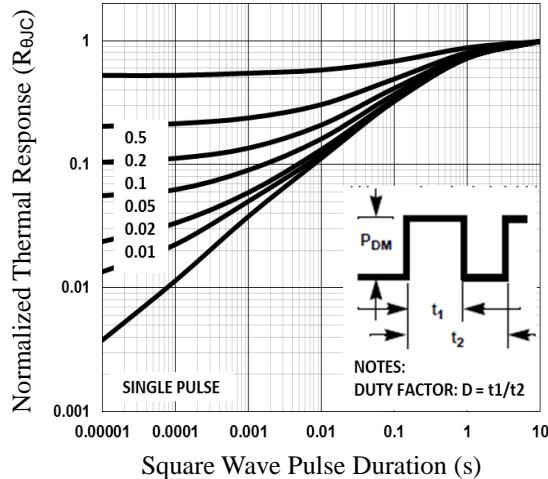


Fig.5 Q1 Normalized Transient Impedance

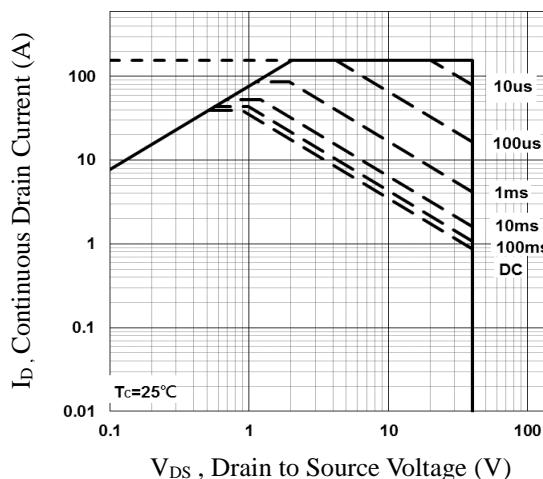


Fig.6 Q1 Maximum Safe Operation Area



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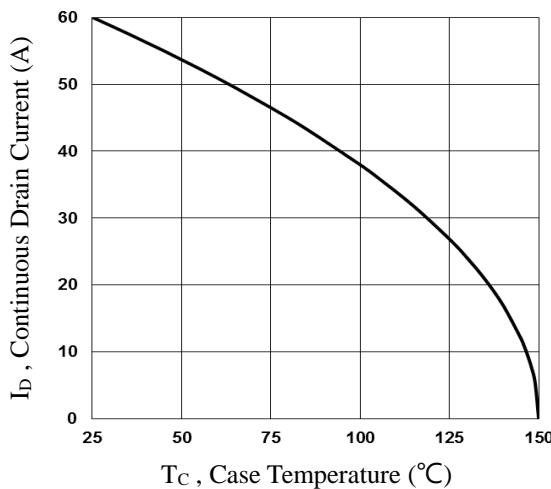


Fig.7 Q2 Continuous Drain Current vs. T_c

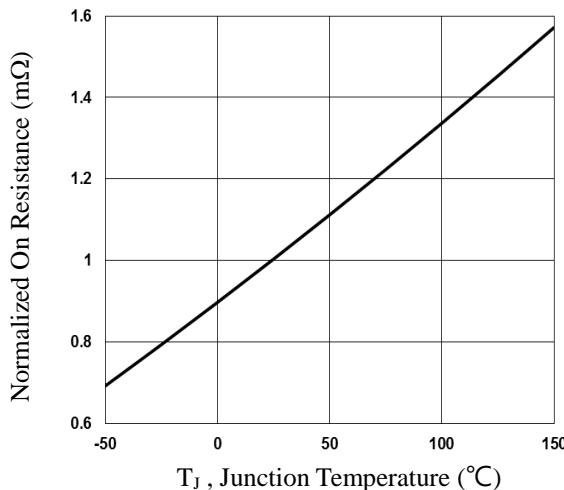


Fig.8 Q2 Normalized R_{DSON} vs. T_j

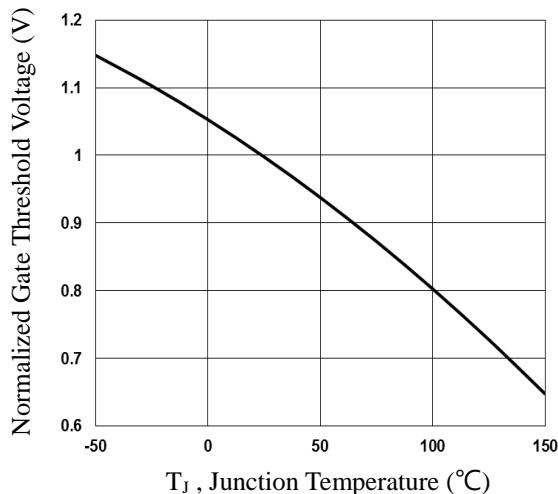


Fig.9 Q2 Normalized V_{th} vs. T_j

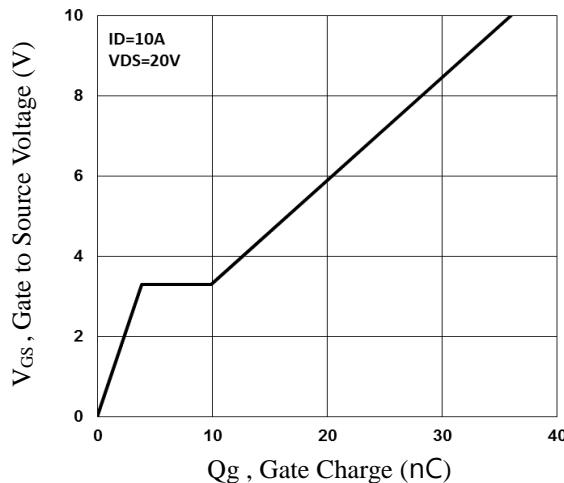


Fig.10 Q2 Gate Charge Waveform

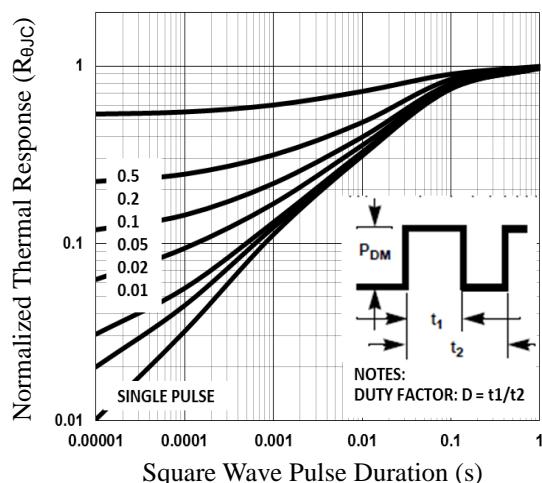


Fig.11 Q2 Normalized Transient Impedance

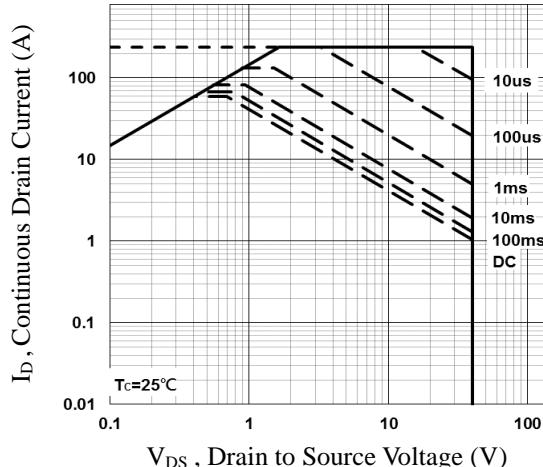


Fig.12 Q2 Maximum Safe Operation Area



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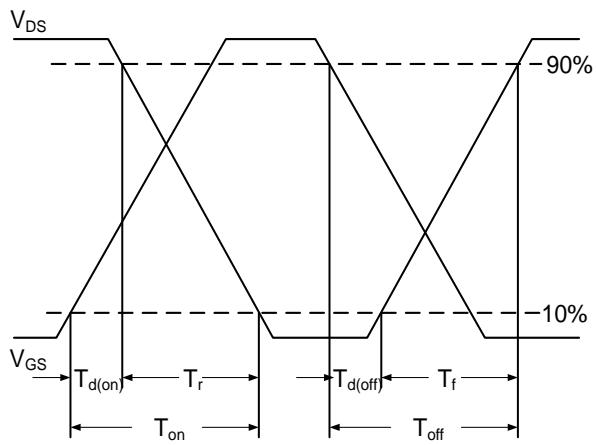


Fig.13 Switching Time Waveform

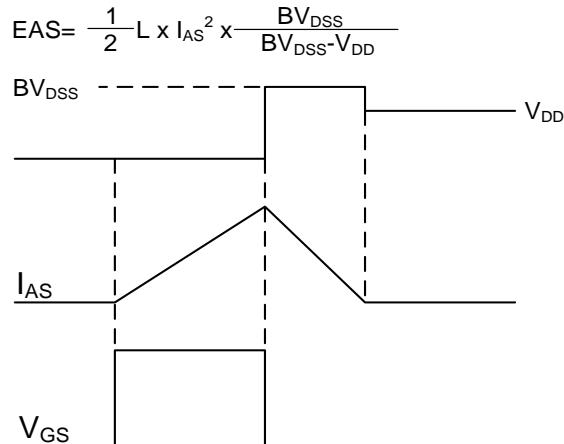
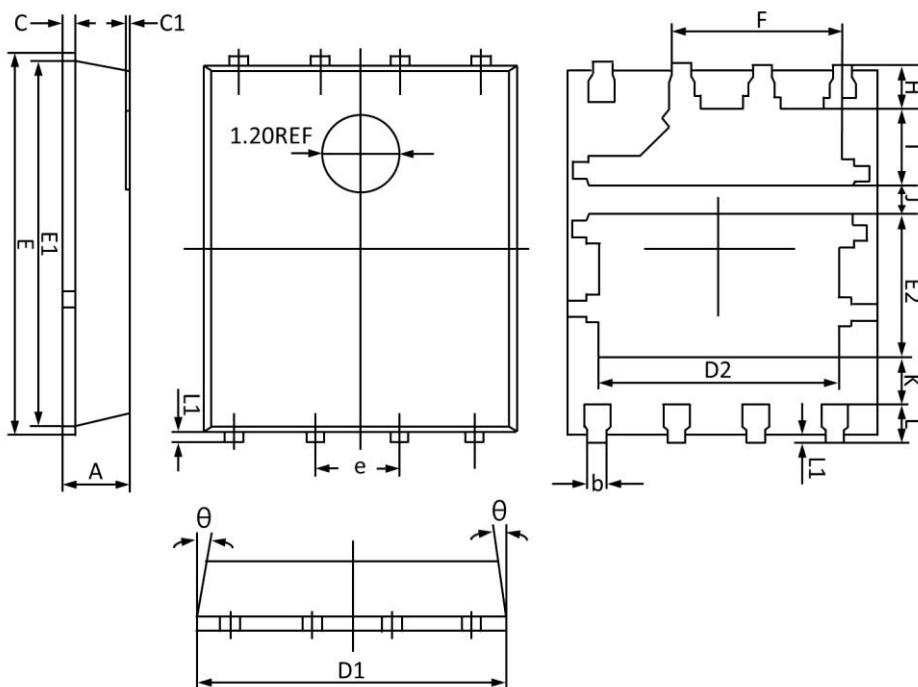


Fig.14 EAS Waveform



PPAK5x6 Asymmetric Dual Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	0.900	1.100	0.036	0.043
b	0.330	0.510	0.013	0.020
C	0.200	0.300	0.008	0.011
C1	0.040 REF		0.040 REF	
D1	4.800	5.000	0.189	0.196
D2	3.610	3.960	0.143	0.155
E	5.900	6.100	0.233	0.240
E1	5.700	5.800	0.225	0.228
E2	2.020	2.420	0.080	0.095
e	1.270BSC		1.270BSC	
F	2.550	2.900	0.101	0.114
H	0.610	0.810	0.025	0.031
I	1.100	1.300	0.044	0.051
J	0.400	0.600	0.016	0.023
K	0.500	-	0.020	-
L	0.510	0.710	0.020	0.027
L1	0.060	0.200	0.003	0.007
θ	0°	12°	0°	12°